Issue Classification	Application/Control No. 10050168	Applicant(s)/Patent under Reexamination KONDOH ET AL.
[barcode]	Examiner: Lee, Jinhee J	Art Unit: 2831

ISSUE CLASSIFICATION

ORIGINAL				CROSS REFERENCE(S)						
CLASS	SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
174	72a		0	72R	95	69	71R	2		

INTERNATIONAL CLASSIFICATION						
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Jinhee Lee (Assistant Examiner)	2/4/05 (Date)	*Dean A. Reichard* 2/5/05 DEAN A. REICHARD SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 (Primary Examiner) (Date)	Total Claims Allowed: 3
Dorian Evans (Legal Instrument Examiner)	2/7/05 (Date)		O.G. Print Claim(s): 1 O.G. Print Fig.: 1

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